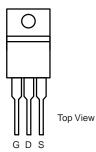


PSMN008-75P-VB Datasheet N-Channel 80 V (D-S) MOSFET

PRODUCT SUMMARY		
V _{DS}	80	V
$R_{DS(on)}$ $V_{GS} = 10$ V	7	mΩ
$R_{DS(on)}$ $V_{GS} = 4.5$ V	9	mΩ
I _D	100	А
Configuration	Sin	gle



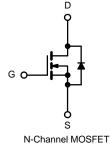


FEATURES

- Trench Power MOSFET
- 100 % $\rm R_g$ and UIS Tested

APPLICATIONS

- Primary Side Switching
- Synchronous Rectification
- DC/AC Inverters
- LED Backlighting



ABSOLUTE MAXIMUM RATINGS (T _A = 25 °C, unless	s otherwise no	ited)	
Parameter		Symbol	Limit	Unit
Drain-Source Voltage		V _{DS}	80	v
Gate-Source Voltage		V _{GS}	± 20	v
	T _C = 25 °C		100ª	
Continuous Drain Current (T. 150 °C)	T _C = 70 °C		85 ^a	
Continuous Drain Current (T _J = 150 °C)	T _A = 25 °C	- I _D -	28.6 ^{b, c}	
	T _A = 70 °C		24.9 ^{b, c}	A
Pulsed Drain Current (t = 100 µs)		I _{DM}	350	
Captinuous Source Drain Diado Current	T _C = 25 °C		80 ^a	
Continuous Source-Drain Diode Current	T _A = 25 °C	I _S	4.5 ^{b, c}	
Single Pulse Avalanche Current	L = 0.1 mH	I _{AS}	30	
Single Pulse Avalanche Energy	L = 0.1 IIIA	E _{AS}	45	mJ
	T _C = 25 °C		180	
Maximum Dawar Dissinction	T _C = 70 °C		120	w
Maximum Power Dissipation	T _A = 25 °C	P _D	5 ^{b, c}	
	T _A = 70 °C		3.2 ^{b, c}	
Operating Junction and Storage Temperature Ra	ange	T _J , T _{stg}	- 55 to 150	ാം
Soldering Recommendations (Peak Temperature)			260	

THERMAL RESISTANCE RATINGS							
Parameter		Symbol	Typical	Maximum	Unit		
Manimum handlan ta Ambianta	$t \le 10 \text{ sec}$	R _{thJA}	15	18			
Maximum Junction-to-Ambient ^a	Steady State	1 thJA	40	50	°C/W		
Maximum Junction-to-Case		R _{thJC}	0.85	1.1			

Notes

- a. Package limited.
- b. Surface mounted on 1" x 1" FR4 board.

c. t = 10 s.



Parameter	Symbol	Test Conditions	Min.	Тур.	Max.	Unit
Static				•	•	
Drain-Source Breakdown Voltage	V _{DS}	$V_{GS} = 0 V, I_{D} = 250 \mu A$	80			V
V _{DS} Temperature Coefficient	$\Delta V_{DS}/T_J$	L 050 A		37		
V _{GS(th)} Temperature Coefficient	$\Delta V_{GS(th)}/T_J$	I _D = 250 μA		- 6.1		mV/°C
Gate-Source Threshold Voltage	V _{GS(th})	$V_{DS} = V_{GS}, I_D = 250 \ \mu A$	2.0		3.5	V
Gate-Source Leakage	I _{GSS}	$V_{DS} = 0 V, V_{GS} = \pm 20 V$			± 100	nA
		$V_{DS} = 80 \text{ V}, V_{GS} = 0 \text{ V}$			1	_
Zero Gate Voltage Drain Current	IDSS	V _{DS} = 80 V, V _{GS} = 0 V, T _J = 55 °C			10	μA
On-State Drain Current ^a	I _{D(on)}	$V_{DS} \ge 5 \text{ V}, \text{ V}_{GS} = 10 \text{ V}$	85			А
	_ (0.1)	V _{GS} = 10 V, I _D = 20 A		7	+	
Drain-Source On-State Resistance ^a	R _{DS(on)}	V _{GS} = 6 V, I _D = 15 A		7.5		mΩ
		V _{GS} = 4.5 V, I _D = 10 A		9		-
Forward Transconductance ^a	g _{fs}	V _{DS} = 10 V, I _D = 20 A		60		S
Dynamic ^b						
Input Capacitance	C _{iss}			3855		
Output Capacitance	C _{oss}	V _{DS} = 40 V, V _{GS} = 0 V, f = 1 MHz		1120		pF
Reverse Transfer Capacitance	C _{rss}			376		
		$V_{DS} = 40 \text{ V}, V_{GS} = 10 \text{ V}, I_{D} = 10 \text{ A}$		35.5		
Total Gate Charge	Qg	$V_{DS} = 40 \text{ V}, V_{GS} = 6 \text{ V}, I_D = 10 \text{ A}$	22			1
				18		nC
Gate-Source Charge	Q _{gs}	$V_{DS} = 40 \text{ V}, V_{GS} = 4.5 \text{ V}, I_{D} = 10 \text{ A}$		5.3		
Gate-Drain Charge	Q _{gd}			7.3		
Output Charge	Q _{oss}	$V_{DS} = 40 \text{ V}, V_{GS} = 0 \text{ V}$		57	86	
Gate Resistance	Rg	f = 1 MHz	0.5	1.3	2	Ω
Turn-On Delay Time	t _{d(on)}			12	24	
Rise Time	t _r	$V_{DD} = 40 \text{ V}, \text{ R}_{\text{I}} = 4 \Omega$		8	16	-
Turn-Off DelayTime	t _{d(off)}	$I_D \cong 10$ Å, $V_{GEN} = 10$ V, $R_g = 1$ Ω		32	64	-
Fall Time	t _f			7	14	
Turn-On Delay Time	t _{d(on)}			14	28	ns
Rise Time	t _r	$V_{DD} = 40 \text{ V}, \text{ R}_{1} = 4 \Omega$		11	22	-
Turn-Off DelayTime	t _{d(off)}	$I_D \cong 10$ Å, $V_{GEN} = 6.0$ V, $R_g = 1$ Ω		30	60	
Fall Time	t _f			8	16	
Drain-Source Body Diode Characteristic	s				•	
Continuous Source-Drain Diode Current	ا _S	T _C = 25 °C			75	^
Pulse Diode Forward Current (t = 100 µs)	I _{SM}				150	A
Body Diode Voltage	V _{SD}	I _S = 5 A		0.76	1.1	V
Body Diode Reverse Recovery Time	t _{rr}			38	75	ns
Body Diode Reverse Recovery Charge	Q _{rr}			36	70	nC
Reverse Recovery Fall Time	ta	I _F = 10 A, dl/dt = 100 A/μs, T _J = 25 °C		19		
Reverse Recovery Rise Time	t _b			19		ns

Notes

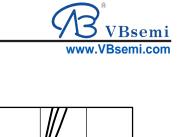
a. Pulse test; pulse width \leq 300 µs, duty cycle \leq 2 %.

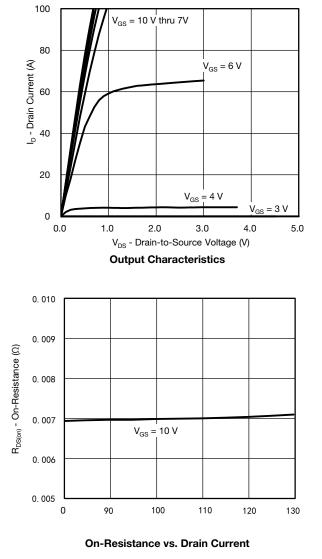
b. Guaranteed by design, not subject to production testing.

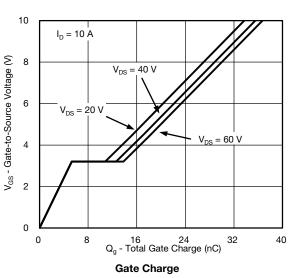
VBsemi VBsemi.com

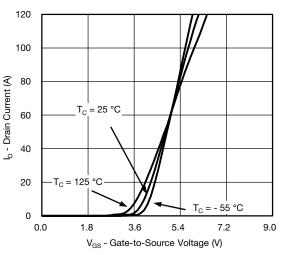
www.

Stresses beyond those listed under "Absolute Maximum Ratings" may cause permanent damage to the device. These are stress ratings only, and functional operation of the device at these or any other conditions beyond those indicated in the operational sections of the specifications is not implied. Exposure to absolute maximum rating conditions for extended periods may affect device reliability.

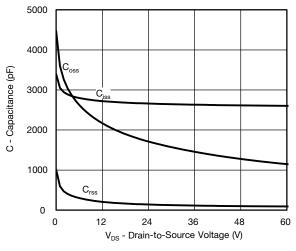




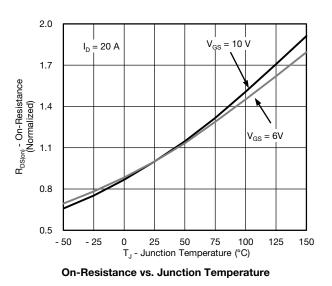




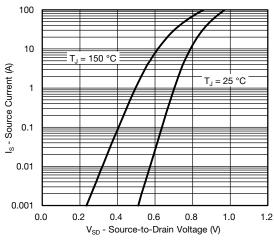
Transfer Characteristics



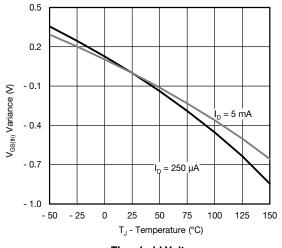




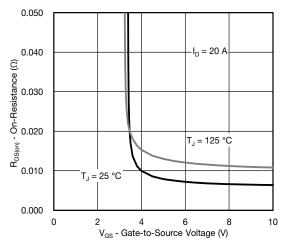




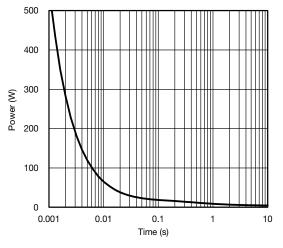
Source-Drain Diode Forward Voltage



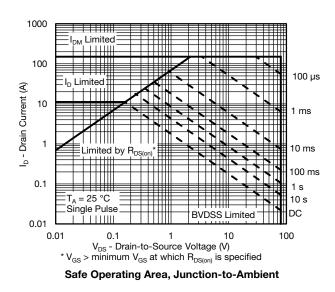
Threshold Voltage



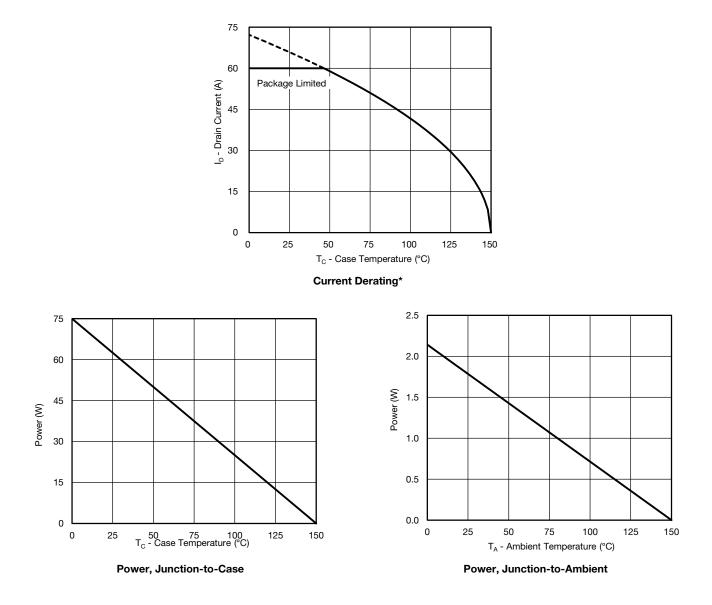
On-Resistance vs. Gate-to-Source Voltage



Single Pulse Power, Junction-to-Ambient

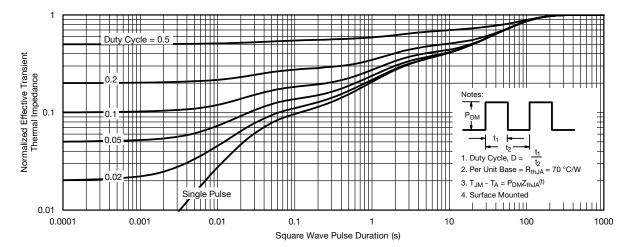




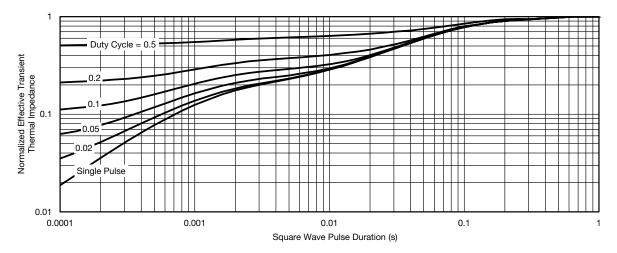


* The power dissipation P_D is based on $T_{J(max.)} = 150$ °C, using junction-to-case thermal resistance, and is more useful in settling the upper dissipation limit for cases where additional heatsinking is used. It is used to determine the current rating, when this rating falls below the package limit.





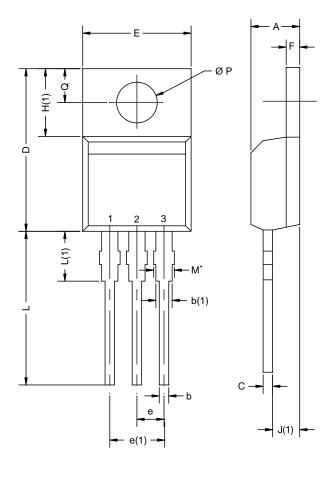
Normalized Thermal Transient Impedance, Junction-to-Ambient



Normalized Thermal Transient Impedance, Junction-to-Case



TO-220AB



	MILLIN	IETERS	INCHES		
DIM.	MIN.	MAX.	MIN.	MAX.	
А	4.25	4.65	0.167	0.183	
b	0.69	1.01	0.027	0.040	
b(1)	1.20	1.73	0.047	0.068	
С	0.36	0.61	0.014	0.024	
D	14.85	15.49	0.585	0.610	
Е	10.04	10.51	0.395	0.414	
е	2.41	2.67	0.095	0.105	
e(1)	4.88	5.28	0.192	0.208	
F	1.14	1.40	0.045	0.055	
H(1)	6.09	6.48	0.240	0.255	
J(1)	2.41	2.92	0.095	0.115	
L	13.35	14.02	0.526	0.552	
L(1)	3.32	3.82	0.131	0.150	
ØР	3.54	3.94	0.139	0.155	
Q	2.60	3.00	0.102	0.118	
ECN: X12- DWG: 547	0208-Rev. N, 1	08-Oct-12			

Notes

 * M = 1.32 mm to 1.62 mm (dimension including protrusion) Heatsink hole for HVM



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